

AUTOMOTIVE GRADE

AUIRLS3034-7P

HEXFET® Power MOSFET

Features

- Advanced Process Technology
- Ultra Low On-Resistance
- · Logic Level Gate Drive
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching

Description

· Repetitive Avalanche Allowed up to Timax

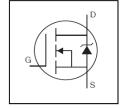
Specifically designed for Automotive applications, this HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of

this design are a 175°C junction operating temperature, fast

switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in Automotive applications and a wide variety

- Lead-Free, RoHS Compliant
- Automotive Qualified *

of other applications.



V _{DSS}	40V
R _{DS(on)} typ.	1.0m Ω
max.	1.4mΩ
D (Silicon Limited)	380A①
D (Package Limited)	240A



G	D	S
Gate	Drain	Source

Ī	Page Dout Number	Dookogo Typo	Standar	d Pack	Ordereble Port Number
	Base Part Number	Package Type	Form	Quantity	Orderable Part Number
ĺ	AUIRLS3034-7P	D ² Pak 7 Pin	Tube	50	AUIRLS3034-7P
	AUIRLS3034-7P	D Pak / Pill	Tape and Reel Left	800	AUIRLS3034-7TRL

Absolute Maximum Ratings

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless otherwise specified.

Symbol	Symbol Parameter		Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	380①	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	270①	1
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Package Limited)	240	A
I _{DM}	Pulsed Drain Current ②	1540	
P _D @T _C = 25°C	Maximum Power Dissipation	380	W
	Linear Derating Factor	2.5	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
E _{AS} Single Pulse Avalanche Energy (Thermally Limited) ③		250	mJ
I _{AR} Avalanche Current ②		See Fig.14,15, 22a, 22b	Α
E _{AR}	Repetitive Avalanche Energy ②		mJ
dv/dt	Peak Diode Recovery @	1.3	V/ns
TJ	Operating Junction and	-55 to + 175	
T _{STG}	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	

Thermal Resistance

THOUSANT TROOTERS				
Symbol	Parameter	Тур.	Max.	Units
$R_{ heta JC}$	Junction-to-Case 9 ®		0.40	°C/W
$R_{\theta,JA}$	Junction-to-Ambient ®		40	C/VV

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^{*}Qualification standards can be found at www.infineon.com



Static @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	40			V	$V_{GS} = 0V, I_{D} = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.035		V/°C	Reference to 25°C, I _D = 5mA ②
			1.0	1.4	mΩ	V _{GS} = 10V, I _D = 200A ⑤
$R_{DS(on)}$	Static Drain-to-Source On-Resistance		1.2	1.7	1112.2	$V_{GS} = 4.5V, I_D = 180A$ (§)
$V_{GS(th)}$	Gate Threshold Voltage	1.0		2.5	V	$V_{DS} = V_{GS}$, $I_D = 250\mu A$
gfs	Forward Trans conductance	370			S	V _{DS} = 10V, I _D = 220A
R_G	Gate Resistance		1.9		Ω	
	Drain to Source Leakage Current			20		$V_{DS} = 40V, V_{GS} = 0V$ $V_{DS} = 40V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I _{DSS}	Drain-to-Source Leakage Current			250	μA	$V_{DS} = 40V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
	Gate-to-Source Forward Leakage			100	nA	V _{GS} = 20V
I _{GSS}	Gate-to-Source Reverse Leakage			-100] ''A	V _{GS} = -20V

Dynamic Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

•	• ·	•	,		
Q_g	Total Gate Charge	 120	180		I _D = 170A
Q_{gs}	Gate-to-Source Charge	 32		~~	V _{DS} = 20V V _{GS} = 4.5V⑤
Q_{gd}	Gate-to-Drain Charge	 71		nC	V _{GS} = 4.5V ^⑤
Q _{sync}	Total Gate Charge Sync. (Q _g - Q _{gd})	 49			
$t_{d(on)}$	Turn-On Delay Time	 71			$V_{DD} = 26V$
t _r	Rise Time	 590		no	I _D = 220A
$t_{d(off)}$	Turn-Off Delay Time	 94		ns	$R_G = 2.7\Omega$
t _f	Fall Time	 200			V _{GS} = 4.5V ^⑤
C_{iss}	Input Capacitance	 10990			$V_{GS} = 0V$
C_{oss}	Output Capacitance	 2030			V _{DS} = 40V
C_{rss}	Reverse Transfer Capacitance	 1100		pF	f = 1.0MHz
Coss eff.(ER)	Effective Output Capacitance (Energy Related)	 2520			V_{GS} = 0V, V_{DS} = 0V to 32V $ \odot $
Coss eff.(TR)	Effective Output Capacitance (Time Related)	 3060			$V_{GS} = 0V, V_{DS} = 0V \text{ to } 32V$ (6)

Diode Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current (Body Diode)			380①		MOSFET symbol showing the
I _{SM}	Pulsed Source Current (Body Diode) ②			1540	A	integral reverse p-n junction diode.
V_{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 200A, V_{GS} = 0V $
t _{rr}	Reverse Recovery Time		46		ı ne	$T_J = 25^{\circ}C$ $V_{DD} = 34V$
۲rr	Treverse recovery Time		49		113	$T_J = 125^{\circ}C$ $I_F = 220A$,
0	Reverse Recovery Charge		100		nC	$T_{J} = 25^{\circ}C$ di/dt = 100A/µs ⑤
Q_{rr}	Treverse recovery charge		110		110	$T_{J} = 125^{\circ}C$
I _{RRM}	Reverse Recovery Current		3.7		Α	T _J = 25°C
t _{on}	Forward Turn-On Time	Intrinsio	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)			

Notes:

- ① Calculated continuous current based on maximum allowable junction temperature. Bond wire current limit is 240A. Note that current limitations arising from heating of the device leads may occur with some lead mounting arrangements.
- ② Repetitive rating; pulse width limited by max. junction temperature.
- ③ Limited by T_{Jmax} , starting $T_J = 25$ °C, L = 0.010mH, $R_G = 25\Omega$, $I_{AS} = 220$ A, $V_{GS} = 10$ V. Part not recommended for use above this value.
- ⑤ Pulse width $\leq 400 \mu s$; duty cycle $\leq 2\%$.
- © Coss eff. (TR) is a fixed capacitance that gives the same charging time as Coss while VDS is rising from 0 to 80% VDSS.
- \odot C_{oss} eff. (ER) is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.
- When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994
- \mathfrak{P}_{θ} is measured at T_J approximately 90°C.
- R_{θJC} value shown is at time zero



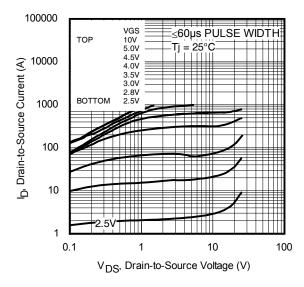


Fig. 1 Typical Output Characteristics

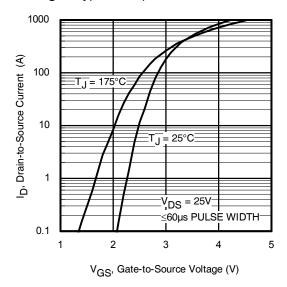


Fig. 3 Typical Transfer Characteristics

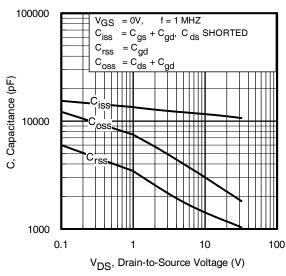


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

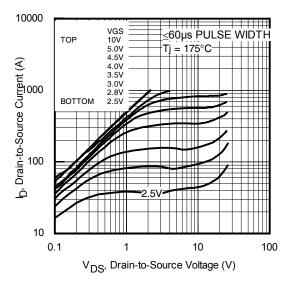


Fig. 2 Typical Output Characteristics

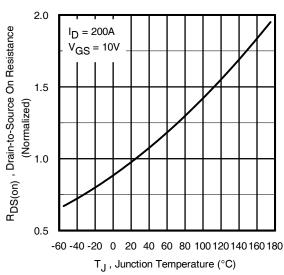


Fig. 4 Normalized On-Resistance vs. Temperature

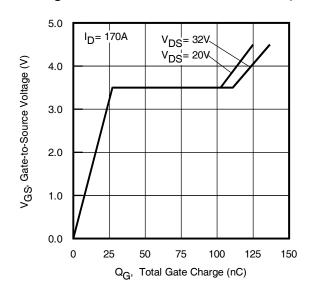


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage



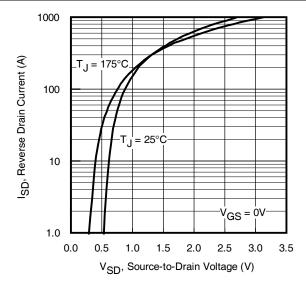


Fig. 7 Typical Source-to-Drain Diode

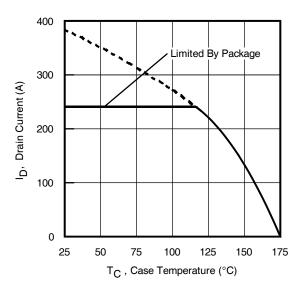


Fig 9. Maximum Drain Current vs. Case Temperature

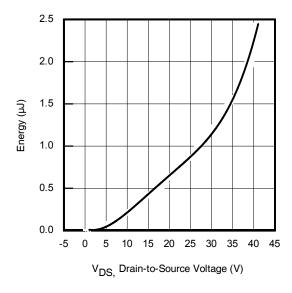


Fig 11. Typical Coss Stored Energy

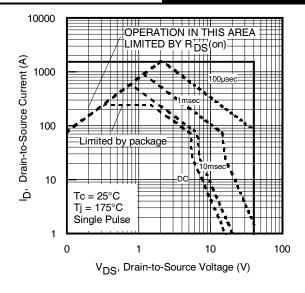


Fig 8. Maximum Safe Operating Area

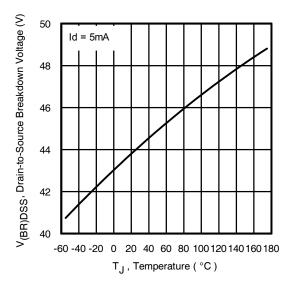


Fig 10. Drain-to-Source Breakdown Voltage

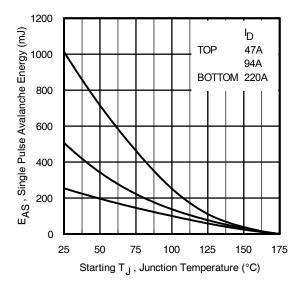


Fig 12. Maximum Avalanche Energy vs. Drain Current

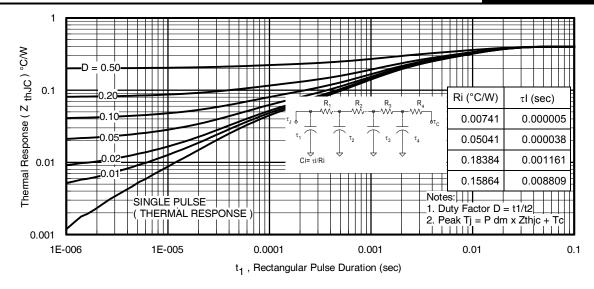


Fig 13. Maximum Effective Transient Thermal Impedance, Junction-to-Case

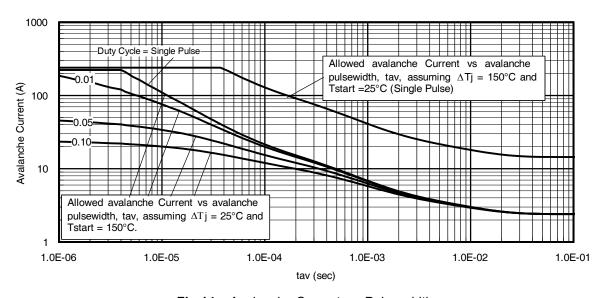


Fig 14. Avalanche Current vs. Pulse width

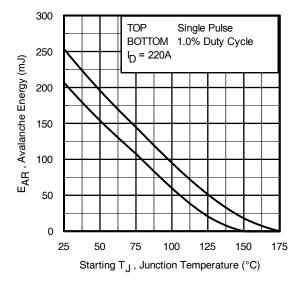


Fig 15. Maximum Avalanche Energy vs. Temperature

Notes on Repetitive Avalanche Curves , Figures 14, 15: (For further info, see AN-1005 at www.infineon.com)

- Avalanche failures assumption:
 Purely a thermal phenomenon and failure occurs at a temperature far in excess of Tjmax. This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long as Tjmax is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 22a, 22b.
- 4. PD (ave) = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. Iav = Allowable avalanche current.
- 7. ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 13, 14).

tav = Average time in avalanche.

D = Duty cycle in avalanche = tav ·f

ZthJC(D, tav) = Transient thermal resistance, see Figures 13)

$$\begin{split} P_{D \; (ave)} &= 1/2 \; (\; 1.3 \cdot BV \cdot I_{av}) = \Delta T/ \; Z_{thJC} \\ I_{av} &= 2\Delta T/ \; [1.3 \cdot BV \cdot Z_{th}] \\ E_{AS \; (AR)} &= P_{D \; (ave)} \cdot t_{av} \end{split}$$



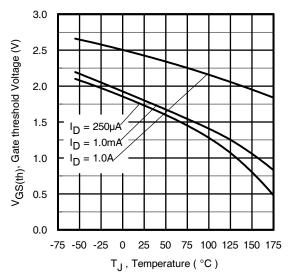


Fig 16. Threshold Voltage vs. Temperature

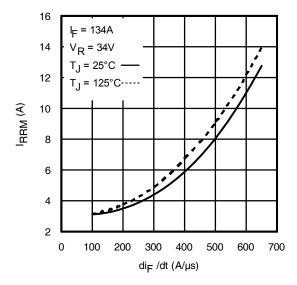


Fig. 18 - Typical Recovery Current vs. dif/dt

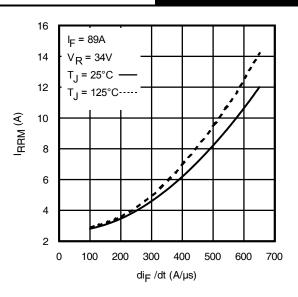


Fig. 17 - Typical Recovery Current vs. dif/dt

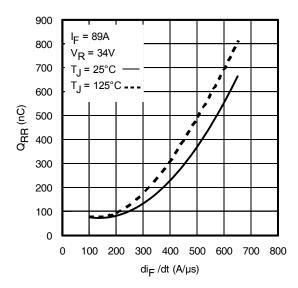


Fig. 19 - Typical Stored Charge vs. dif/dt

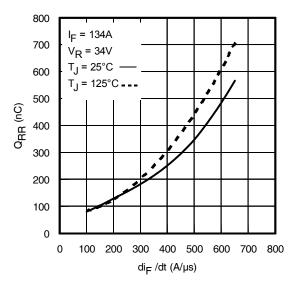


Fig. 20 - Typical Stored Charge vs. dif/dt

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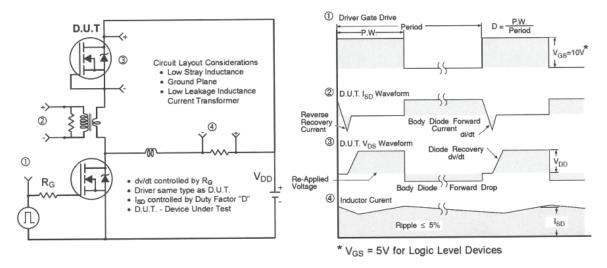


Fig 21. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

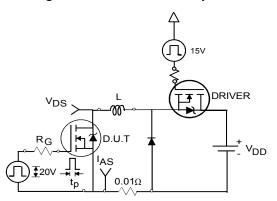


Fig 22a. Unclamped Inductive Test Circuit

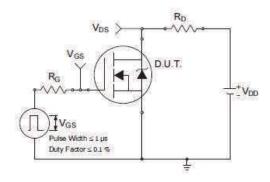


Fig 23a. Switching Time Test Circuit

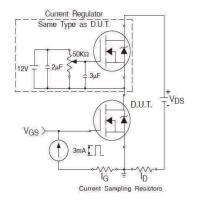


Fig 24a. Gate Charge Test Circuit

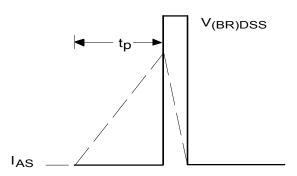


Fig 22b. Unclamped Inductive Waveforms

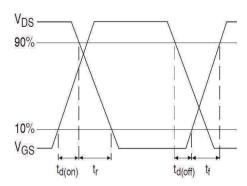


Fig 23b. Switching Time Waveforms

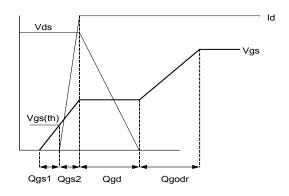
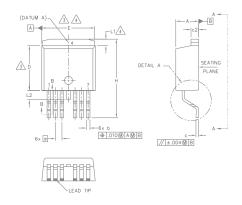
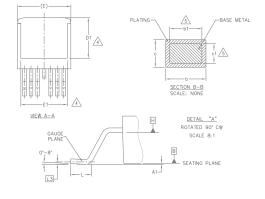


Fig 24b. Gate Charge Waveform



D²Pak - 7 Pin Package Outline (Dimensions are shown in millimeters (inches))





S Y M	DIMENSIONS						
B	MILLIM	ETERS	INC	HES	O T E S		
L	MIN.	MAX.	MIN.	MAX.	E S		
Α	4.06	4.83	.160	.190			
A1	_	0.254	_	.010			
Ь	0.51	0.99	.020	.036			
b1	0.51	0.89	.020	.032	5		
С	0.38	0.74	.015	.029			
с1	0.38	0.58	.015	.023	5		
c2	1.14	1.65	.045	.065			
D	8.38	9.65	.330	.380	3		
D1	6.86	7.42	.270	.292	4		
E	9.65	10.54	.380	.415	3,4		
E1	6.22	8.48	.245	.334	4		
е	1.27 BSC		.050	BSC			
Н	14.61	15.88	.575	.625			
L	1.78	2.79	.070	.110			
L1	_	1.68	_	.066	4		
L2	_	1.78	_	.070			
L3	0.25	BSC	.010	BSC			

NOTES:

- 1. DIMENSIONING AND TOLERANCING AS PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

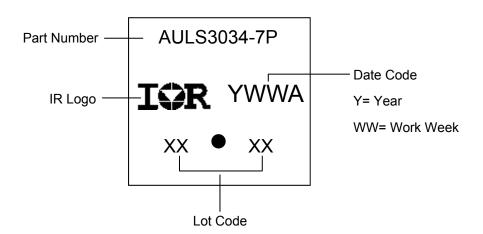
O.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

5. DIMENSION 61 AND c1 APPLY TO BASE METAL ONLY.

- 6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 7. CONTROLLING DIMENSION: INCH.
- 8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-263CB. EXCEPT FOR DIMS. E, E1 & D1.

D²Pak - 7 Pin Part Marking Information



Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



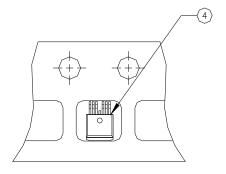
D²Pak - 7 Pin Tape and Reel

NOTES, TAPE & REEL, LABELLING:

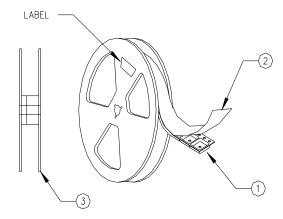
- 1. TAPE AND REEL.
 - 1.1 REEL SIZE 13 INCH DIAMETER.
 - 1.2 EACH REEL CONTAINING 800 DEVICES.
 - 1.3 THERE SHALL BE A MINIMUM OF 42 SEALED POCKETS CONTAINED IN THE LEADER AND A MINIMUM OF 15 SEALED POCKETS IN THE TRAILER.
 - 1.4 PEEL STRENGTH MUST CONFORM TO THE SPEC. NO. 71-9667.
 - 1.5 PART ORIENTATION SHALL BE AS SHOWN BELOW.
 - 1.6 REEL MAY CONTAIN A MAXIMUM OF TWO UNIQUE LOT CODE/DATE CODE COMBINATIONS.

 REWORKED REELS MAY CONTAIN A MAXIMUM OF THREE UNIQUE LOT CODE/DATE CODE COMBINATIONS.

 HOWEVER, THE LOT CODES AND DATE CODES WITH THEIR RESPECTIVE QUANTITIES SHALL APPEAR ON THE BAR CODE LABEL FOR THE AFFECTED REEL.



- 2. LABELLING (REEL AND SHIPPING BAG).
 - 2.1 CUST. PART NUMBER (BAR CODE): IRFXXXXSTRL-7P
 - 2.2 CUST. PART NUMBER (TEXT CODE): IRFXXXXSTRL-7P
 - 2.3 I.R. PART NUMBER: IRFXXXXSTRL-7P
 - 2.4 QUANTITY:
 - 2.5 VENDOR CODE: IR
 - 2.6 LOT CODE:
 - 2.7 DATE CODE:



Note: For the most current drawing please refer to IR website at http://www.irf.com/package/

2015-11-4



Qualification Information

		Automotive (per AEC-Q101)				
Qualificat	ion Level	Comments: This part number(s) passed Automotive qualification. Infineon's Industrial and Consumer qualification level is granted by extension of the higher Automotive level.				
Moisture Sensitivity Level D²-Pak 7 Pin MSL1						
	Machine Model		Class M4 (+/- 800V) [†]			
	iviaci ii ie iviodei	AEC-Q101-002				
ECD	Human Dady Madal	Class H3A (+/- 6000V) [†]				
ESD	Human Body Model	AEC-Q101-001				
	Charred Davisa Madal	Class C5 (+/- 2000V) [†]				
	Charged Device Model		AEC-Q101-005			
RoHS Co	mpliant	Yes				

[†] Highest passing voltage.

Revision History

Date	Comments						
	Added "Logic Level Gate Drive" bullet in the features section on page 1						
4/2/2014	Updated part marking on page 8						
4/2/2014	 Updated typo on the fig.19 and fig.20, unit of y-axis from "A" to "nC" on page 6. 						
	Updated data sheet with new IR corporate template						
11/4/2015	Updated datasheet with corporate template						
11/4/2015	Corrected ordering table on page 1.						

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